



si255

HYPERION Optical Sensing Instrument



Luna's Micron Optics HYPERION si255 is an industrial grade fan-less optical sensing interrogator. Featuring both static and dynamic full spectrum analysis, the si255 provides long-term, reliable and accurate measurements of nearly 1000 sensors on 16 parallel, 160 nm wide channels.

The si255 features an all new, high power, low noise, ultra wide swept wavelength laser with guaranteed absolute accuracy on every scan, which is realized with Micron Optics patented Fiber Fabry-Perot filter and wavelength reference technology.

The HYPERION platform features groundbreaking capabilities including on-board, high-performance DSP and real-time FPGA processing. This enables rapid, full-spectrum data acquisition and flexible peak detect algorithms of Fiber Bragg Gratings (FBG), Long Period Gratings, Fabry-Perot (FP) and Mach-Zehnder (MZ) sensors with low-latency access to data for closed loop feedback applications.

The HYPERION platform is now compatible with ENLIGHT Sensing Analysis Software, which provides an integrated suite of tools for data acquisition, computation and analysis of optical sensor networks.

The HYPERION platform also includes a comprehensive Application Programming Interface (API) and examples written in LabVIEW, Python, Matlab, C++ and C#.

KEY FEATURES

- **Standard, High Speed and Enhanced Visibility** models, each with an available depolarized source and up to 16 parallel channels
- **Dynamic and absolute measurements of FBGs, LPGs, FP and MZ sensors** from detailed optical spectrum
- **Deep, continuous dynamic range** is available to each sensor on each channel, independent of differential system losses
- **Data verification key guarantees only valid output.** Each data set is calibrated and verified against a permanent NIST traceable reference.
- **Proven reliability and longevity of the Micron Optics swept wavelength source**, with over 100 million hours logged since 2000

DEPLOYMENTS

- Oil & gas
- Medical devices
- Industrial measurements
- Energy
- Structures
- Security
- Aerospace

Dynamic and absolute measurements of FBG & FP sensors on 16 parallel, 160 nm wide channels and ENLIGHT compatible

PERFORMANCE

Performance Properties			
Measurement option	Enhanced visibility, 10 Hz	Standard, 100 or 1000 Hz	High speed, 5000 Hz
Number of channels	4, 8 or 16 parallel channels	4, 8 or 16 parallel channels	4, 8 or 16 parallel channels
Wavelength range	1500-1600 or 1460-1620 nm	1500-1600 or 1460-1620 nm	1500-1580 or 1510-1590 nm
Wavelength accuracy/stability ¹	1 pm / 1pm	1 pm / 1pm	2 pm / 3 pm
Wavelength repeatability ²	1 pm, 0.3 pm at 1 Hz	1 pm, 0.05 pm at 1 Hz	2 pm, 0.05 pm at 1 Hz
Dynamic range/continuous	35 dB peak / 45 dB FS	25 dB peak / 40 dB FS	17 dB peak / 40 dB FS
Full spectrum measurement ³	Included, data rate at 10 Hz	Included, data rate at 10 Hz	Included, data rate at 10 Hz
Optical connectors	LC/APC		
Compatible sensors ⁴	Fiber Bragg Gratings, Long Period Gratings, Fabry-Perot and Mach-Zehnder Interferometers		
Depolarizer Option Available ⁵	Yes		
Interfaces and Software			
Interface	Ethernet		
Software	Comprehensive API and example support for LabVIEW™, Python, Matlab, C++ and C#		
Physical Properties			
Dimensions/weight	307 mm x 274 mm x 69 mm / 4.9 kg		
Operating/storage conditions	-20 to 60 C, < 80%RH non-condensing / -30 to 70 C, < 95%RH non-condensing		
Input voltage	9 - 36 VDC, AC/DC converter included (100~240 VAC, 47~63 Hz)		
Power consumption at 12 V	30 W typ, 40 max		

EXAMPLE CONFIGURATIONS

si255-ST-04-1500-1600-0100-NO	4 ch si255 ST with 1500-1600 nm scan range, 100 Hz scan rate and no internal accessories
si255-EV-08-1460-1620-0010-DP	8 ch si255 EV with 1460-1620 nm scan range, 10Hz scan rate and internal depolarizer option
si255-ST-16-1460-1620-1000-FR	16 ch si255 ST with 1460-1620 nm scan range, 1 kHz scan rate and full redundancy option

ORDERING

si255-mm-cc-lwvl-uwvl-ssss-aa

mm	Measurement option	EV	Enhanced visibility
		ST	Standard
		HS	High speed
cc	Number of channels	04	4 channel
		08	8 channels
		16	16 channels
lwvl	Lower wavelength in nanometers		
uwvl	Upper wavelength in nanometers		
ssss	Scan rate in Hz		
aa	Internal Accessory Option	NO	None
		DP	Depolarizer
		FR	Full Redundancy (16 ch only)

ACCESSORIES

x55_rkm	19" rack mount kit	x55_atx	19" ATEX certified
x55_skm	Surface mount kit	x55_ew3	3 year extended warranty
x55_cas	x55 transport case	oa2001	LC/APC-FC/APC connectivity kit

NOTES

1. Accuracy per NIST Technical Note 1297, 1994 Edition, Section D.1.1.1, definition of "accuracy of measurement." Stability captures effects of long term use over operating temperature range.
2. Per NIST Technical Note 1297, 1994 Edition, Sect D.1.1.2, definition of "repeatability [of results of measurements]."
3. For faster scan rates >10 Hz, data bandwidth may limit rate of multichannel spectral streams.
4. FBG bandwidths of 0.25 nm used for performance qualification.
5. Details regarding the Depolarized Laser Option are available in the x55 Depolarized Laser Option Technical Note.



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